Compliant with IEC 62474/ D9.00

MICROCHIP Semiconductor Device Type: P and PL (S2X) 040 PDIP .600in Matte Tin				Termination Base Alloy: Copper Alloy (Cu)			Package Homogeneous Materials			
Genniconductor Device Type.	1 and 1 L	"Contained In"	% Total							e3
Basic Substance	CAS Number	Sub-Component	Weight	mg/part	ppm	5157.75	(mg) Total	Mold Compound	% ot Total Weight	79.35
Fused Silica	60676-86-0	Mold Compound	57.132	3713.580	571,320		Fused Silica	60676-86-0	72.00	
Metal Hydro Oxide	Trade Secret	Mold Compound	8.729	567.353	87,285		Metal Hydro Oxide	Trade Secret	11.00	
Epoxy Resin Phenol Resin	Trade Secret Trade Secret	Mold Compound Mold Compound	5.555 5.555	361.043 361.043	55,545 55,545		Epoxy Resin Phenol Resin	Trade Secret Trade Secret	7.00 7.00	
SiO2	14808-60-7	Mold Compound	1.984	128.944	19,838		SiO2	14808-60-7	2.50	
Carbon Black	1333-86-4	Mold Compound	0.397	25.789	3,968		Carbon Black	1333-86-4	0.50	
Copper	7440-50-8	Lead Frame Tape	9.984	648.938	99,837			Total	100.00	
Iron	7439-89-6	Lead Frame Tape	0.246	15.962	2,456	679.25	(mg) Total	Lead Frame	% of Total Weight	10.45
Silver	7440-22-4	Lead Frame Tape	0.199	12.940	1,991		Copper	7440-50-8	95.54	
Zinc	7440-66-6	Lead Frame Tape	0.013	0.849	131		Iron	7439-89-6	2.35	
Phosphorous	7723-14-0	Lead Frame Tape	0.009	0.560	86		Silver	7440-22-4	1.91	
Polyimide	25038-81-7	Lead Frame Tape	0.215	13.975	2,150		Zinc	7440-66-6	0.13	
Poly - ethylene – terephthalate	25038-59-9	Lead Frame Tape	0.190 0.035	12.350	1,900 350		Phosphorous	7723-14-0	0.08	
NBR Bismaleimide	9003-18-3	Lead Frame Tape		2.275		20.52	(m. m) =	Total		
	79922-55-7	Lead Frame Tape	0.030	1.950	300	32.50	(mg) Total	Lead Frame Tape	% of Total Weight	0.5
Phenol resin	153-20-5 / 9016-8	Lead Frame Tape	0.030 0.550	1.950 35.763	300 5,502	D-	Polyimide	25038-81-7 25038-59-9	43.00	
Silver Epoxy Resin	7440-22-4 9003-36-5	Die Attach Die Attach	0.550	7.152	1,100	PO	y - ethylene – terephthalate NBR	9003-18-3	38.00 7.00	
Diluent	3101-60-8	Die Attach	0.055	3.573	550		Bismaleimide	79922-55-7	6.00	
Phenolic hardener	Trade secret	Die Attach	0.022	1.428	220		Phenol resin	28453-20-5 / 9016-83-5	6.00	
Amine type hardener	827-43-0	Die Attach	0.011	0.717	110		T HOHOL TOOLL	Total	100.00	
Dicyandiamide	461-58-5	Die Attach	0.002	0.117	18	48.75	(mg) Total	Die Attach	% of Total Weight	0.75
Silicon	7440-21-3	Chip (Die)	7.500	487.500	75.000	-10.10	Silver	7440-22-4	73.36	
Copper	7440-50-8	Wire Bond palladium coated copper (CuPd)	0.197	12.773	1,965		Epoxy Resin	9003-36-5	14.67	
Palladium	7440-05-3	Wire Bond palladium coated copper (CuPd)	0.004	0.228	35		Diluent	3101-60-8	7.33	
Tin	7440-31-5	Plating on external leads (pins) - Matte Tin / annealed at 150°C for 1 hour	1.250	81.250	12,500		Phenolic hardener	Trade secret	2.93	
		TOTALS:	100.000	6,500.000	1,000,000		Amine type hardener	827-43-0	1.47	
	6.5000	g Total Mass					Dicyandiamide	461-58-5	0.24	
is semiconductor device and its homogenous materials comply w 15) and 2002/53/EC (End-of-Life Vehicles (ELV) without exemption		: 2002/95/EC (27 January 2003) & Directive 2011/65/EU (08	luma 2044) an						0.24	
10) and 2002/00/20 (Line-or-Line verifices (LLV) without exemption	(zero)		June 2011) an	nd 2015/863/E	U (31 March			Total	100.00	
ompliance with the above EU Directives has been verified via inter	. ,		June 2011) an	nd 2015/863/E	U (31 March	487.50	Total (mg)			7.5
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